Application/Control No. Notice of References Cited Application/Control No. 10/564,404 Examiner Scott R. Wilson Applicant(s)/Patent Under Reexamination LEE, SUK-HUN Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,906,352	06-2005	Edmond et al.	257/94
*	В	US-6,201,262	03-2001	Edmond et al.	257/77
*	С	US-6,015,979	01-2000	Sugiura et al.	257/86
*	D	US-6,657,234	12-2003	Tanizawa, Koji	257/79
	Е	US-			
	F	US-			
	G	US-		·	
	Н	US-			
	1	US-			
	J	US-			
	К	US-			
4	L	US-			
	М	US-			,

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP02002016284A	01-2002	Japan	Suzuki et al.	H01L033/00
	0					
	Р	-				
	Q					
	R					
	s					
	Т					<u> </u>

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)						
	U							
	V							
	w							
	x							

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.